	Application No.	Applicant(s)
	10/808,787	MORSE, MICHAEL T.
Notice of Allowability	Examiner	Art Unit
	James D. Stein	2874
The MAILING DATE of this communication appe All claims being allowable, PROSECUTION ON THE MERITS IS (herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGOR (The Office or upon petition by the applicant. See 37 CFR 1.313	ars on the cover sheet wi (OR REMAINS) CLOSED it or other appropriate common GHTS. This application is a and MPEP 1308.	th the correspondence address n this application. If not included unication will be mailed in due course. THIS
1. This communication is responsive to <u>divisional application in the second se</u>	filed 3/23/2004.	
2. The allowed claim(s) is/are <u>1-9</u> .		
3. \boxtimes The drawings filed on <u>23 March 2004</u> are accepted by the B	Examiner.	
 4. Acknowledgment is made of a claim for foreign priority un a) All b) Some* c) None of the: 1. Certified copies of the priority documents have 2. Certified copies of the priority documents have 3. Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: 	been received. been received in Application	on No
Applicant has THREE MONTHS FROM THE "MAILING DATE" on noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.		a reply complying with the requirements
5. A SUBSTITUTE OATH OR DECLARATION must be submit INFORMAL PATENT APPLICATION (PTO-152) which give		
6. CORRECTED DRAWINGS (as "replacement sheets") mus	t be submitted.	
(a) I including changes required by the Notice of Draftspers	on's Patent Drawing Review	v (PTO-948) attached
1) 🔲 hereto or 2) 🔲 to Paper No./Mail Date		·
(b) including changes required by the attached Examiner's Paper No./Mail Date	Amendment / Comment o	in the Office action of
Identifying indicia such as the application number (see 37 CFR 1. each sheet. Replacement sheet(s) should be labeled as such in the	84(c)) should be written on t ne header according to 37 CF	he drawings in the front (not the back) of R 1.121(d).
7. DEPOSIT OF and/or INFORMATION about the depose attached Examiner's comment regarding REQUIREMENT F		
Attachment(s) 1. ☑ Notice of References Cited (PTO-892) 2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)	6. Interview S	formal Patent Application (PTO-152)
3. ⊠ Information Disclosure Statements (PTO-1449 or PTO/SB/0		/Mail Date Amendment/Comment
Paper No./Mail Date 1204 4. Examiner's Comment Regarding Requirement for Deposit of Biological Material	8. ⊠ Examiner's 9. ☐ Other	PHAN T. H. PALMER PRIMARY EXAMINER
		12/27/2004

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DETAILED ACTION

EXAMINER'S AMENDMENT Andt / JOS

An examiner's amendment to the record appears below. Should the changes and/or additions be unacceptable to applicant, an amendment may be filed as provided by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be submitted no later than the payment of the issue fee.

The application has been amended as follows: In paragraph [0001], "[Attorney Docket No. 42P13840]" is replaced with "10/160625, filed 05/31/2002". Also, "[Attorney Docket No. 42P13842]" is replaced with "10/159379, filed 05/31/2002".

Allowable Subject Matter

Claims 1-9 are allowed.

The following is an examiner's statement of reasons for allowance: None of the cited prior art taken alone or in combination anticipates or obviates the claimed invention. In particular, removing a portion of the protective layer so as to define a taper footprint, and subsequently form said taper from a semiconductor layer, which is grown using a selective silicon epitaxy process, is not taught by the prior art. Upon completing said taper growth, said taper is treated with chemical mechanical polishing. In this manner a smooth, *unetched* taper may be formed, resulting in less optical power loss upon coupling. In contrast, the related prior art only teaches forming a taper portion from a *previously* grown semiconductor layer by etching or polishing said semiconductor

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layer so as to form a desired taper shape. See for example, USPAT 6,813,432 to Salib. Furthermore, if the prior art does teach forming said taper portion by selective epitaxial growth, a further etching stage is also taught in order to adjust said taper portion to form a desired shape. Such would *not* result in said taper having "at least one unetched surface," as claimed by applicant. See for example, USPAT 6,816,660 to Nashimoto.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

Conclusion

The prior art made of record and not relied upon is considered pertinent to applicant's disclosure. USPAT 6,813,432 to Salib, and USPAT 6,816,660 to Nashimoto, which disclose related methods of forming tapered waveguides on a substrate.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to James D. Stein whose telephone number is (571) 272-2132. The examiner can normally be reached on M-F (8:00am-4:30pm).

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Rodney Bovernick can be reached on (571) 272-2344. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

James D. Stein

PHAN T. H. PALMER PRIMARY EXAMINER

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12/27/2004